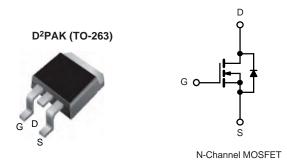


H7N0401LS-VB Datasheet N-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, c}	Q _g (Typ.)		
40	0.0017 at V _{GS} = 10 V	150	120 nC		
	0.0025 at V_{GS} = 4.5 V	135	120110		



FEATURES

- Trench Power MOSFET
- 100 % R_g and UIS Tested

APPLICATIONS

- Synchronous Rectification
- Power Supplies

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	40	V		
Gate-Source Voltage		V _{GS}		± 25	
	T _C = 25 °C		150 ^{a, c}		
Continuous Drain Current (T 175 °C)	T _C = 70 °C		120 ^c		
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	29 ^b		
	T _A = 70 °C		23 ^b	A	
Pulsed Drain Current		I _{DM}	380	-	
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	80		
Single Pulse Avalanche Energy		E _{AS}	320	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	110 ^{a, c}	A	
Continuous Source-Drain Diode Current	T _A = 25 °C	'S	2.6 ^b	A	
	T _C = 25 °C		312 ^a	w	
Maximum Power Dissipation	T _C = 70 °C	P	200		
	T _A = 25 °C	P _D	3.13 ^b		
	T _A = 70 °C		2.0 ^b	7	
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^b	Steady State	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.33	0.4	C/VV	

Notes:

a. Based on $T_C = 25 \ ^{\circ}C$.

b. Surface Mounted on 1" x 1" FR4 board.

c. Calculated based on maximum junction temperature. Package limitation current is 110 A.

SPECIFICATIONS T _J = 25 °C, unless otherwise noted Parameter Symbol Text Conditions Min Text Conditions							
Parameter Static	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 µA	45			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	VGS = 0 V, ID = 200 µ/V	40	41		w mV/°C V	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	= 250 µA		- 8			
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	1.2	- 0	2.5		
Gate-Source Leakage		$V_{\rm DS} = V_{\rm GS}, \ B = 200 \ \mu \text{A}$ $V_{\rm DS} = 0 \ \text{V}, \ V_{\rm GS} = \pm 20 \ \text{V}$	1.2		± 100	nA	
Gale-Source Leakage	I _{GSS} I _{DSS}	$V_{DS} = 40 \text{ V}, \text{ V}_{GS} = 20 \text{ V}$				IIA	
Zero Gate Voltage Drain Current		$V_{DS} = 40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ $V_{DS} = 40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 \text{ °C}$			1 10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 V$, $V_{GS} = 10 V$	120			Α	
Drain-Source On-State Resistance ^a	D(011)	V _{GS} = 10 V, I _D = 30 A		0.0017		- Ω	
	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 20 A		0.0025			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 30 A		180		S	
Dynamic ^b		·		1		1	
Input Capacitance	C _{iss}			9000		pF	
Output Capacitance	C _{oss}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		650			
Reverse Transfer Capacitance	C _{rss}			450			
Total Gate Charge	Qg			120	180	nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = 20$ V, $V_{GS} = 10$ V, $I_{D} = 20$ A		30			
Gate-Drain Charge	Q _{gd}			16			
Gate Resistance	Rg	f = 1 MHz		0.85	1.3	Ω	
Turn-On Delay Time	t _{d(on)}			20	30		
Rise Time	t _r	V_{DD} = 20 V, R_L = 1.0 Ω		11	17	- ns	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ 20 A, V_{GEN} = 10 V, R_g = 1 Ω		77	115		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			102	155		
Rise Time	t _r	V_{DD} = 20 V, R_L = 1.0 Ω		62	95		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 20$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		180	270		
Fall Time	t _f			60	90		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			110	A	
Pulse Diode Forward Current ^a	I _{SM}				200	A	
Body Diode Voltage	V _{SD}	I _S = 20 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			50	75	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L = 20.4 di/dt = 100.4/up T = 25.00		70	105	nC	
everse Recovery Fall Time t _a		I _F = 20 A, di/dt = 100 A/μs, T _J = 25 °C		30			
Reverse Recovery Rise Time	t _b)		20		ns	

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

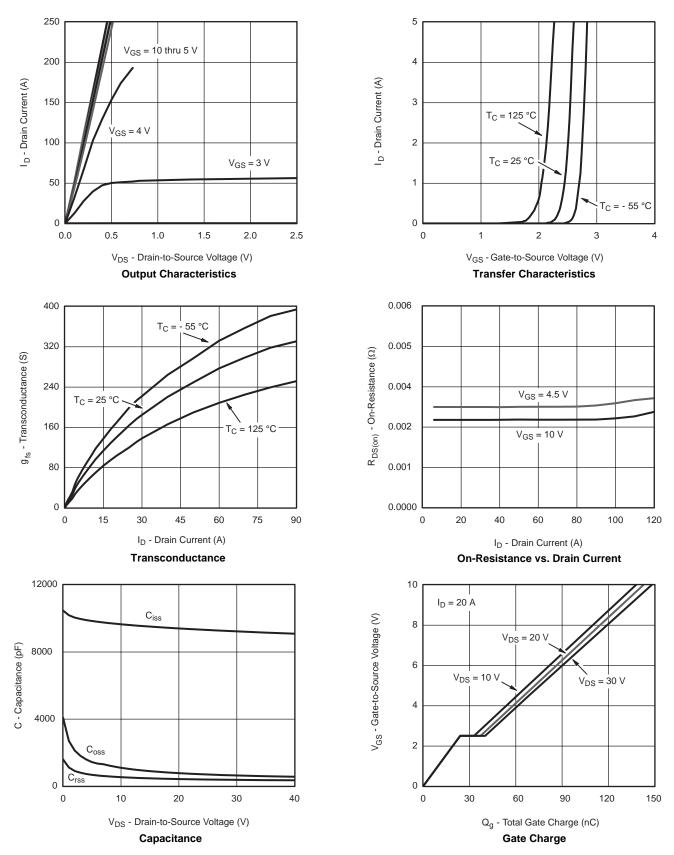
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



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2.0 100 I_D = 30 A 1.7 10 $V_{GS} = 10 V$ R_{DS(on)} - On-Resistance I_S - Source Current (A) T_J = 150 °C T_J = 25 °C (Normalized) 1.4 1 $V_{GS} = 4.5 V$ 1.1 0.1 0.8 0.01 0.5 0.001 . 0.0 0.2 0.4 0.6 1.2 0.8 1.0 - 50 - 25 0 25 50 75 100 125 150 V_{SD} - Source-to-Drain Voltage (V) T_J - Junction Temperature (°C) **On-Resistance vs. Junction Temperature** Forward Diode Voltage vs. Temperature 0.6 0.010 0.008 R $_{DS(on)}$ - On-Resistance (Ω) 0.2 V_{GS(th)} Variance (V) 0.006 - 0.2 $I_D = 5 \text{ mA}$ 0.004 T_J = 150 °C - 0.6 0.002 I_D = 250 μA T_J = 25 °C 0.000 - 1.0 2 4 6 8 - 50 - 25 0 25 50 75 100 125 150 0 10 T_J - Temperature (°C) V_{GS} - Gate-to-Source Voltage (V) **Threshold Voltage On-Resistance vs. Gate-to-Source Voltage** 1000 TTT Limited by R_{DS(on)}* 1-1 10 µs 100 100 µs ŦĦ I_D - Drain Current (A) 1 ms -10 10 ms 100 ms, DC 1 $T_C = 25 °C$ 0.1 Single Pulse BVDSS ≣ 111 0.01

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

0.1

1

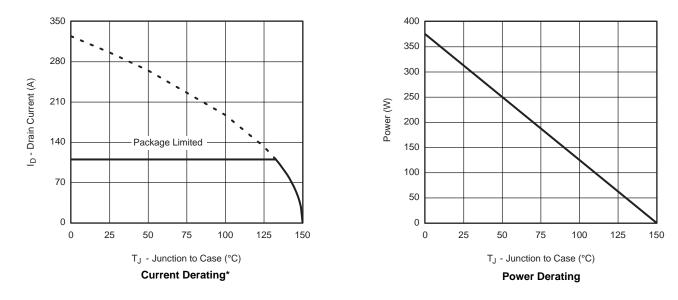
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 $\label{eq:VDS} V_{DS} \mbox{-} Drain-to-Source Voltage (V) $$ V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified $$ Safe Operating Area, Junction-to-Ambient $$$

100

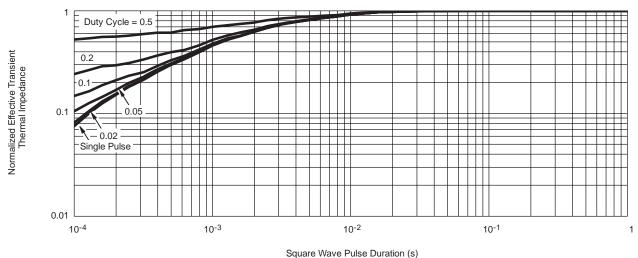
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

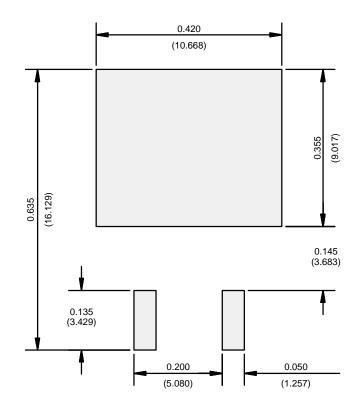
* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



RECOMMENDED MINIMUM PADS FOR D²PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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